



## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants : Makoto KUROSAWA et al. Group Art Unit : 2615

Appl. No. : 10/597,415 Examiner : Not Yet Assigned  
(U.S. National Stage of PCT/JP2005/000933)

I.A. Filed : January 19, 2005 Confirmation No. : 1744

For : PHASE MEASUREMENT DEVICE, METHOD, PROGRAM, AND RECORDING MEDIUM

## INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents  
U.S. Patent and Trademark Office  
Customer Service Window, Mail Stop AMENDMENT  
Randolph Building  
401 Dulany Street  
Alexandria, VA 22314

Sir:

In accordance with the duty of disclosure under 37 C.F.R. §1.56 and §§1.97-1.98, Applicants hereby bring to the attention of the Examiner the following information.

The following documents were cited in an International Search Report with respect to International Patent Application No. PCT/JP2005/000933, of which the present application is the U.S. National Stage Application. A copy of the International Search Report has been filed concurrently with the present application and should thus have already been brought to the attention of the Examiner.

- (1) Japanese Laid-Open Patent Publication No. 2002-228694 A, together with an English language translation of the same;

- (2) Japanese Laid-Open Patent Publication No. 2000-314753 A, together with an English language translation of the same; and
- (3) Japanese Laid-Open Patent Publication No. HEI 7-229944 A, together with an English language translation of the same.

The relevance of the documents cited in the International Search Report, as ascertained with respect to the international claims by the International Examiner, is set forth in the International Search Report.

Applicants further submit the following documents:

- (4) Japanese Laid-Open Patent Publication No. 2001-285211 A, together with an English language translation of the same. Applicants note that this document is cited beginning at page 1 of the specification of the above-captioned application;
- (5) U.S. Patent Application No. 10/556,352 to MARUYAMA et al., which was filed on November 10, 2005;
- (6) U.S. Patent Application No. 10/556,354 to TAKAOKU, which was filed on November 10, 2005;
- (7) U.S. Patent Application No. 10/557,596 to NAKADA, which was filed on November 22, 2005;
- (8) U.S. Patent Application No. 10/597,451 to MIYAUCHI et al., which was filed on July 26, 2006; and
- (9) U.S. Patent Application No. 10/577,254 to NOWARA, which was filed on April 26, 2006.

Further to the U.S. Patent and Trademark Office's decision to waive the requirement under 37 C.F.R. §1.98 (a)(2)(iii) if the U.S. patent application was filed after June 30, 2003, copies of the U.S. patent applications are not enclosed herewith. However, if any copy is needed, the Examiner is respectfully requested to contact the undersigned.

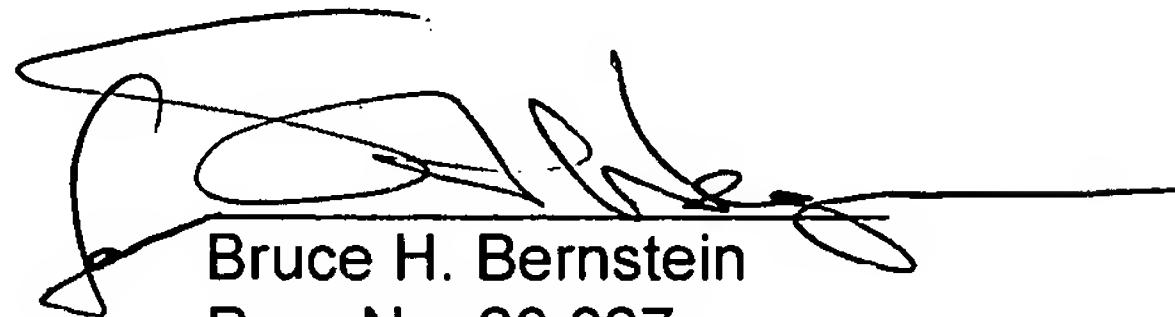
Also, when the above-noted pending applications are published, the Examiner is respectfully requested to list their publication numbers on a PTO 1449 Form (or PTO 892 Form) to confirm consideration thereof.

Applicants respectfully request that the Examiner consider the above material and cite the same. Copies of the above-noted foreign documents, including the noted English language translations, are attached hereto, and all of the documents are listed on an attached PTO-1449 Form. The Examiner is requested to initial the appropriate spaces on the attached Form and to return a copy of the completed Form to Applicants with the next official communication in the present application.

Applicants note that an Office Action on the merits has not issued in the present application, and thus, no fee is believed necessary to ensure consideration of the submitted material.

Should the Examiner have any questions, the Examiner is invited to contact the undersigned at the below-listed telephone number.

Respectfully submitted,  
Makoto KUROSAWA et al.



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**\*EXAMINEE**

## **DATE CONSIDERED**

\*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.